

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of:

HORST HAUSSECKER, ET AL.

Application No.:

Filed:

For: **Model-Based Fusion of Scanning Probe
Microscopic Images for Detection and
Identification of Molecular Structures**

Art Group: 1645

Examiner: Not yet assigned

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure, enclosed is a copy of Information Disclosure Statement by Applicant (form PTO/SB/08), which is being submitted concurrently with the Continuation-in-Part Application. It is respectfully requested that the cited references be considered and that the enclosed copy of PTO/SB/08 be initialed by the Examiner to indicate such consideration and a copy thereof returned to applicant(s). Some or all of the references listed on the enclosed PTO/SB/08 were previously identified in the parent application (Application No. 10/273,312, filed October 17, 2002) and copies of the references were furnished at that time. Accordingly, per 37 CFR §1.98(d)(1) additional copies of those references are not submitted herewith.

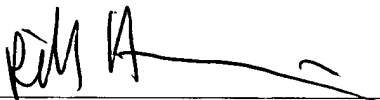
The submission of this Information Disclosure Statement is not to be construed as a representation that a search has been made in the subject application and is not to be construed as an admission that the information cited in this statement is material to patentability.

Please charge any fees due to Deposit Account 02-2666. A duplicate copy of the Fee Transmittal (PTO/SB/17) is enclosed for this purpose.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Date: 10/14/03



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Substitute for form 1449A/PTO (modified) INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete if known	
				Application Number	Not yet assigned
				Filing Date	Concurrently Herewith
				First Named Inventor	Horst Haussecker
				Group Art Unit	Not yet assigned
				Examiner Name	Not yet assigned
Sheet	1	of	3	Attorney Docket	42P14242X

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No. ¹	U.S. Patent Document Number	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Passages or Figures Appear
		5,472,881		Beebe, et al.	12/05/1995	
		5,497,656		Kado, et al.	03/12/1996	
		6,044,221		Gupta, et al.	03/28/2000	
		6,078,681		Silver	06/20/2000	
		6,157,921		Barnhill	12/05/2000	
		6,195,445		Dubuisson-Jolly, et al.	02/27/2001	
		6,259,802		Jolly, et al.	07/10/2001	
		6,280,939		Allen	08/28/2001	
		6,327,581		Platt	12/04/2001	
		6,345,235		Edgecombe, et al.	02/05/2002	
		6,360,020		Panis	03/19/2002	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		United States Patent Application Publication, Publication No. US 2001/0052257, Magerle, Publication Date December 20, 2001.	

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		ANDO, et al., "A High-Speed Atomic Force Microscope for Studying Biological Macromolecules," <i>PNAS</i> , Vol. 98, No. 22, pp. 12468-12472, October 2001.	
		CLAUSS, et al., "Atomic Resolution STM Imaging of a Twisted Single-Wall Carbon Nanotube," <i>Physical Review B</i> , Volume 58, Number 8, pp. 4266-4269, August 1998.	
		CLAUSS, et al., "Electron Backscattering on Single-Wall Carbon Nanotubes Observed by Scanning Tunneling Microscopy," <i>Europhys. Lett.</i> , 47(5), pp. 601-607, 1999.	
		FREITAG, et al., "Local Electronic Properties of Single-Wall Nanotube Circuits Measured by Conducting-Tip AFM," <i>Physical Review B</i> , Volume 62, Number 4, pp. 2307-2310, July 2000.	
		FRISBIE, et al., "Functional Group Imaging by Chemical Force Microscopy," <i>Science</i> , Vol. 265, pp. 2071-2074, September 1994.	
		HANSMA, et al., Atomic Force Microscopy of DNA in Aqueous Solutions," <i>Nucleic Acids Res.</i> , 21:505-512, 1993.	
		HIRAHARA, et al., "One-Dimensional Metallofullerene Crystal Generated Inside Single-Walled Carbon Nanotubes," <i>Physical Review Letters</i> , Volume 85, Number 25, pp. 5384-5387, December 2000.	
		HUANG, et al., "Directed Assembly of One-Dimensional Nanostructures into Functional Networks," <i>Science</i> , Vol. 291, pp. 630-633, January 2001.	
		KIM, et al., "AFM Study of Surface Phenomena Based on C ₆₀ Film Growth," <i>Applied Surface Science</i> , 130-132, pp.602-609, 1998.	
		KLEIN, et al., "Ordered Stretching of Single Molecules of Deoxyribose Nucleic Acid Between Microfabricated Polystyrene Lines," <i>Applied Physics Letters</i> , Vol. 78, Number 16, pp. 2396-2398, April 2001.	

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		KOBAYASHI, et al., "Imaging of Fullerene Molecules on Si(111)-7 7 Surface with NC-AFM," <i>Applied Surface Science</i> , 157, pp. 228-232, 2000.	
		MÖLLER, et al, "Tapping-Mode Atomic Force Microscopy Produces Faithful High-Resolution Images of Protein Surfaces," <i>Biophys. J.</i> , 77:1150-8, 1999.	
		MURRAY, et al., "Atomic Force Microscopy of Biochemically Tagged DNA," <i>Proc. Natl. Acad. Sci. USA</i> , 90:3811-4, 1993.	
		NICEWARMER-PENˆA, "Submicrometer Metallic Barcodes," <i>Science</i> , Vol. 294, pp. 137-141, October 2001.	
		ODOM, et al., "Single-Walled Carbon Nanotubes," <i>Ann. N.Y. Acad. Sci.</i> , 960: 203-215, (2002). Retrieved from the Internet on July 2, 2002, URL://<http://annalsnyas.org/cgi/content/full/960/1/203> 10 pages.	
		THUNDAT, et al., "Atomic Force Microscopy of DNA on Mice and Chemically Modified Mica," <i>Scanning Microsc.</i> 6:911-8, 1992.	
		UCHIHASHI, et al, "Application of Noncontact-Mode Atomic Force Microscopy to Molecular Imaging," Retrieved from the Internet on July 3, 2002, URL://<http://www.foresight.org/Conferences/MNT7/Abstracts/Uchihashi/> 2 pages.	

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